

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

2877

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TECHNOLOGY CENTER 2800

Re Application of : Ofer Du-nour
Serial No. : 09/762,473
Filed : 7 February 2001
For : Methods And Apparatus For Measuring The
Thickness Of A Film, Particularly Of A Photoresist
Film On A Semiconductor
Attorney Docket No. : 24982

POWER OF ATTORNEY

Director of US Patent and Trademark Office
Washington, D.C. 20231
USA

Sir:

I (we) hereby appoint the following attorneys or agents, with full power of substitution, association, and revocation, to prosecute this application and to transact all business in the Patent and Trademark Office connected therewith;

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I (we) hereby revoke all Powers of Attorney previously granted.

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Signature : [Signature]
Name : Ofer Du-nour
Capacity : Chairman & Dir. of Tech
Date : 13/8/02